

Notice of References Cited	Application/Control No. 08/764,110	Applicant(s)/Patent Under Reexamination CHEN, YUHPYNG L.	
	Examiner Mark L. Berch	Art Unit 1624	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2005/0107343 A1	05-2005	Kasibhatla et al.	514/081
	B	US-2005/0038049 A1	02-2005	Ding et al.	514/265.1
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

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